

DOCKET NO: 213217US-2X

IN THE UNITED STATES PATENT & TRADEMARK OFFICE

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IN RE APPLICATION OF

:

AUG 1 1 2004

HARUO SHINDO ET AL.

: EXAMINER: P. PATEL

**OFFICE OF PETITIONS**

SERIAL NO: 09/935,585

:

FILED: AUGUST 24, 2001

: GROUP ART UNIT: 2829

FOR: METHOD OF MEASURING  
ELECTRON ENERGY DISTRIBUTION IN  
PLASMA REGION AND APPARATUS  
FOR MEASURING THE SAME

:

**PETITION FOR WITHDRAWAL OF  
APPLICATION FROM ISSUE UNDER 37 C.F.R. §1.313(c)(2)**

BOX: DAC  
COMMISSIONER FOR PATENTS  
ALEXANDRIA, VIRGINIA 22313

ATTN: OFFICE OF PETITIONS  
FRANCIS HICKS

SIR:

Applicants hereby petition the Commissioner to withdraw the above-identified application from issue under the provisions of 37 C.F.R. § 1.313(c)(2) in order to permit consideration of an Amendment Under § 1.312 and a Request for Continued Examination filed in compliance with 37 C.F.R. § 1.114. The Issue Fee was paid in this application on July 6, 2004, as evidenced by the enclosed date-stamped filing receipt. A Request for Continued Examination and an Amendment are being concurrently filed herewith. Favorable consideration of this Petition is respectfully requested.

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The required fee of \$130.00 is enclosed herewith by check and any further charges may be made against the Attorney of Record's Deposit Account No. 15-0030. A duplicate copy of this petition is attached.

Respectfully submitted,

OBLON, SPIVAK, McCLELLAND,  
MAIER & NEUSTADT, P.C.



Gregory J. Maier  
Attorney of Record  
Registration No. 25,599

Customer Number  
**22850**

Tel: (703) 413-3000  
Fax: (703) 413 -2220  
(OSMMN 06/04)

Scott A. McKeown  
Registration No. 42,866

GJM:SAM:ycs

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*mjs*

Dept.: IP-II

By: MJS/btm

OSM&N File No. 213217US2X

Serial No. 09/935,585

In the matter of the Application of: Haruo SHINDO, et al.

For: METHOD OF MEASURING ELECTRON ENERGY DISTRIBUTION IN  
PLASMA REGION AND APPARATUS FOR MEASURING THE SAME

Due Date: 7/6/04

The following has been received in the U.S. Patent Office on the date stamped hereon:

☒ Credit Card Form for \$1,630.00  
(Issue Fee \$1330.00 + Pub. Fee \$300.00)

☒ Dep. Acct. Order Form

☒ Issue Fee Transmittal

